

<b>Search Notes</b> 				<b>Application/Control No.</b> 10/710,456 <b>Examiner</b> Huyen Le	<b>Applicant(s)/Patent under Reexamination</b> KEMP ET AL. <b>Art Unit</b> 3751	
<b>SEARCHED</b>				<b>SEARCH NOTES (INCLUDING SEARCH STRATEGY)</b>		
Class	Subclass	Date	Examiner		DATE	EXMR
4	576.1 577.1	7/24/2004				
269	6 68					
	194 212					
	214 215					
<b>INTERFERENCE SEARCHED</b>						
Class	Subclass	Date	Examiner			